

FORM PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTORNEY DOCKET NO. 2077.D1/SILICON/MBE		04/597,378 SERIAL NO. 40A							
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Grumberge, et al.		FILING DATE: Herewith							
				GROUP: 1796		Unknown							
U.S. PATENT DOCUMENTS													
Examiner Initial	DOCKET NUMBER							DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
800	A1*	4	1	9	8	2	6	1	4/15/80	Busia, et al.	156	626	
	A2*	4	2	0	8	2	4	0	6/17/80	Latos	156	627	
	A3*	4	4	9	3	7	4	5	1/15/85	Chen, et al.	156	628	
	A4*	4	8	4	2	6	8	3	6/27/89	Cheng, et al.	156	345	
	A5*	4	8	5	9	2	7	7	8/22/89	Barna, et al.	156	626	
	A6*	4	9	5	3	9	8	2	09/1998	Elbing, et al.	356	357	
	A7*	4	9	7	5	1	4	1	12/04/90	Greco, et al.	156	626	
	A8*	5	0	0	2	6	3	1	03/26/91	Giapis, et al.	156	643	
	A9*	5	2	0	0	0	2	3	4/6/93	Gifford, et al.	156	626	
	A10*	5	3	6	2	3	5	6	11/8/94	Schoenborn	156	626	
	A11*	5	3	7	2	6	7	3	12/1994	Singer, et al.	438	008	
	A12*	5	3	7	2	6	7	3	12/1994	Singer, et al.			DUPLICATE
	A13*	5	3	9	2	1	2	4	2/21/95	Barbee, et al.	356	381	
	A14*	5	3	9	9	2	2	9	3/21/95	Stefani, et al.	156	626	
	A15*	5	4	0	3	4	3	3	4/1995	Morrison, et al.	216	060	
	A16*	5	4	0	6	0	8	0	4/11/95	Friedheim	250	309	
	A17*	5	4	4	5	7	0	5	8/29/95	Barbee, et al.	156	627.1	
	A18*	5	4	5	0	2	0	5	9/12/95	Sawin, et al.	356	382	
	A19*	5	4	5	1	2	8	9	9/19/95	Barbee, et al.	216	059	
	A20*	5	4	5	6	7	8	8	10/10/95	Barbee, et al.	156	345	
	A21*	5	4	6	7	8	8	3	11/21/95	Frye, et al.	216	060	
	A22*	5	4	7	2	5	0	8	12/1995	Saxena	118	723BE	
	A23*	5	5	3	6	3	5	9	7/1996	Kawada, et al.	438	016	
	A24	5	6	5	4	9	0	3	8/5/97	Kelman, et al.	364	651.01	
	A25	5	6	9	1	5	4	0	11/25/97	Halle, et al.	250	372	
	A26*	5	7	1	6	4	5	1	2/10/98	Hama, et al.	118	723	
	A27	5	7	4	7	3	8	0	5/5/98	Yu, et al.	438	599	
	A28*	5	7	7	0	0	9	7	6/1998	O'Neill, et al.	216	060	
	A29*	5	7	9	2	2	7	2	8/1998	Van Os, et al.	118	723R	
80	A30*	5	8	0	7	7	6	1	09/1998	Coronel, et al.	438	014	
EXAMINER: <i>Altman, O'Brien</i>										DATE CONSIDERED: 4/16/02			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTORNEY DOCKET NO. 2077.D1/SILICONMBE			09/595,778 SERIAL NO. 2000						
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)							APPLICANT: Grimbergen, et al.						
							FILING DATE: Herewith		GROUP: 1796 Microcrystalline				
U.S. PATENT DOCUMENTS													
Examiner Initial	A31	5	8	3	4	3	7	5	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>AW</i>	A31	5	8	3	4	3	7	5	11/10/98	Chen	438	692	09/595,778 06/16/00
<i>AW</i>	A32*	5	8	4	6	8	8	3	12/8/98	Moslehi	438	711	
	A33												
	A34												
	A35												
	A36												
	A37												
	A38												
	A39												
	A40												
	A41												
	A42												
	A43												
	A44												
	A45												
	A46												
	A47												
	A48												
	A49												
	A50												
	A51												
	A52												
	A53												
	A54												
	A55												
	A56												
	A57												
	A58												
	A59												
	A60												
EXAMINER	<i>Ma a. Ohe</i>										DATE CONSIDERED 9/16/02		

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered.
Include copy of this form with next communication to applicant.

FORM PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTORNEY DOCKET NO. 2077 DI/USA/SILICON/MBE				09/895.773 SERIAL NO. -WA								
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Grimbergen, ET AL.				GROUP: <u>Unknown</u>								
				FILING DATE: Herwith												
FOREIGN PATENT DOCUMENTS																
		DOCKET NUMBER								DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION		
														YES	NO	
<i>Alc</i>	B1*	0	7	3	5	5	6	5	02/10/96	EP APPLICATION						
<i>Alc</i>	B2	0	7	5	6	3	1	8	1/19/97	EP APPLICATION	<i>H01L</i>	<i>21/46</i>				
<i>Alc</i>	B3*	0	7	8	8	1	3	8	08/06/97	EP APPLICATION						
	B4															
	B5															
	B6															
	B7															
	B8															
	B9															
	B10															
	B11															
	B12															
	B13															
	B14															
	B15															
	B16															
	B17															
	B18															
	B19															
	B20															
	B21															
	B22															
	B23															
	B24															
	B25															
	B26															
	B27															
	B28															
	B29															
	B30															
EXAMINER: <i>Allen W. Olson</i>										DATE CONSIDERED: <i>7/14/02</i>						

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTORNEY DOCKET NO. 2007.DI/USA/SILICON/MBE		09/15/95, 778 SERIAL NO. 166	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Grinberger, et al.		FILING DATE: Herewith	
				GROUP: Unknown		174	
OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)							
Acw	C1*	International Search Report, dated February 17, 1999					
1	C2*	Principles of Instrumental Analysis, 2 nd Ed., Skoog and West (Saunders, 1980) pages 181, 182, 193, 245					
	C3*	Sofie Instruments- Product User's Manual, Digitwin DATE UNKNOWN					
	C4*	"In-Situ Control and Diagnosis of Deposition and Etch Processes is Possible Using Interferometry Combined with CCD Imaging", European Semi-Conductor, March 1995, pages 14-17					
Acw	C5*	F. Heinrich, P. Kopperschmidt, "Online Uniformity Measurements in Large Area Plasma Assisted Etching and Deposition", Proceedings of the 10 th International Colloquium on Plasma Processes CIP '95", Antibes, France, June 11-15 1995					
	C6						
	C7						
	C8						
	C9						
	C10						
	C11						
	C12						
	C13						
	C14						
	C15						
	C16						
	C17						
	C18						
	C19						
	C20						
EXAMINER							
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							